## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TAKAGI ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0010059 A1	07-2001	BURMAN et al.	709/224
*	В	US-2001/0034839 A1	10-2001	Karjoth et al.	713/190
*	С	US-2003/0061333 A1	03-2003	Dean et al.	709/223
*	D	US-2003/0046383 A1	03-2003	Lee et al.	709/224
*	Е	US-2004/0030741 A1	02-2004	Wolton et al.	709/202
*	F	US-6,771,661 B1	08-2004	Chawla et al.	370/468
*	G	US-2004/0151187 A1	08-2004	Lichtenstein, Walter D.	370/395.21
*	Н	US-6,829,648 B1	12-2004	Jones et al.	709/230
*	ı	US-6,987,753 B2	01-2006	Liu et al.	370/348
*	J	US-7,068,769 B1	06-2006	Weaver et al.	379/201.1
	К	US-			
	L	US-			
	М	US-	[.		

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
L	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-PATENT DOCUMENTS						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
<del>-</del>	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.